

**Flexible Translucent Persistent Luminescence Films Based on  
 $\text{Sr}_2\text{MgSi}_2\text{O}_7:\text{Eu}^{2+},\text{Dy}^{3+}$  Cellulose Ether Composites**

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**Supplementary Information**

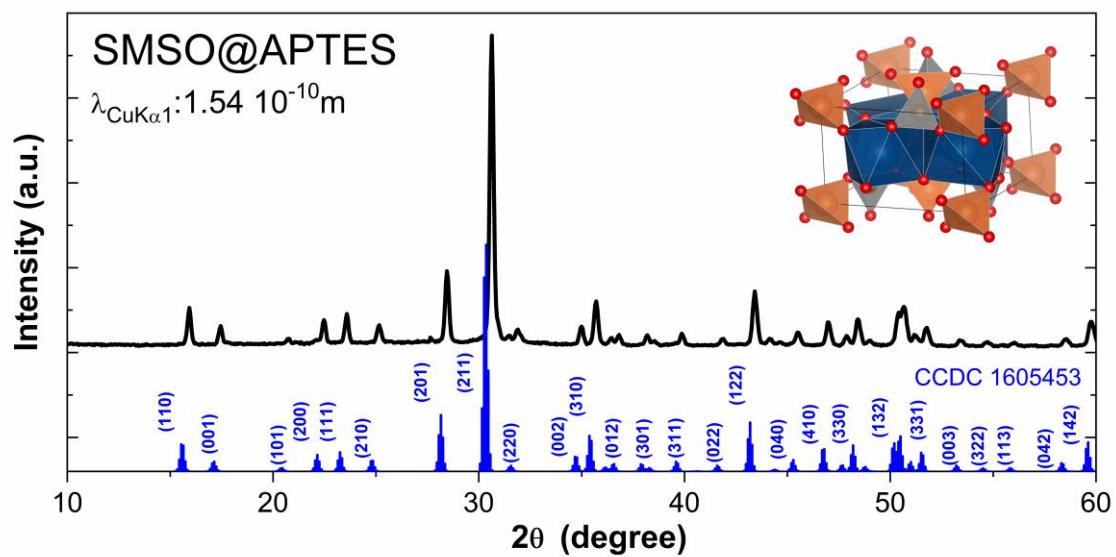


Figure S1: SMSO@APTES crystallography, CCDC 1605453 pattern as a reference for SMSO.

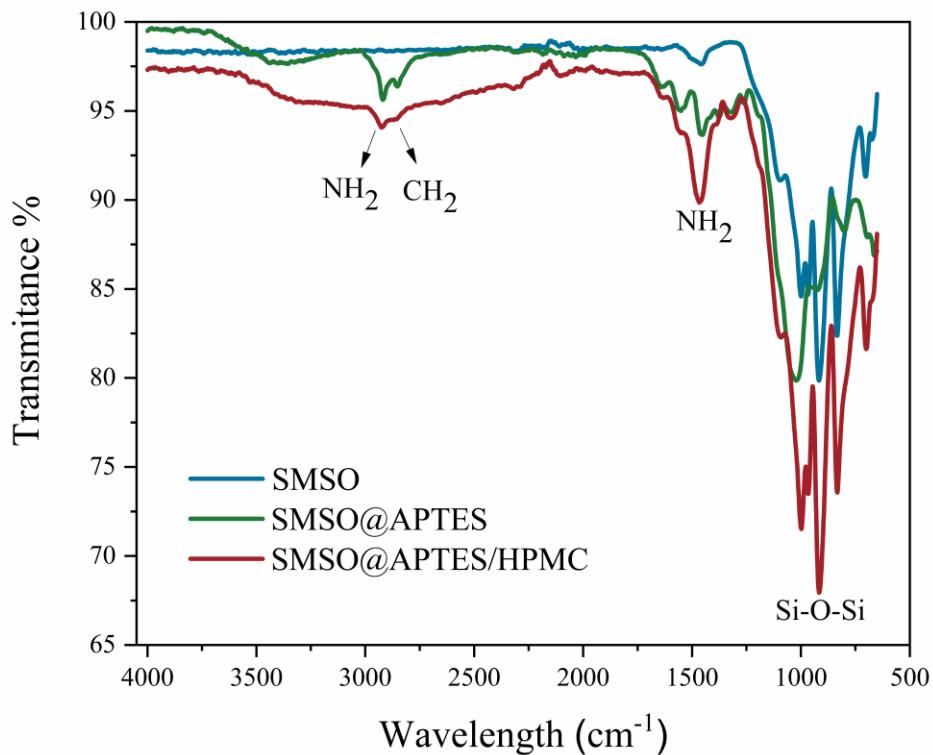


Figure S2: FTIR spectrum of SMSO NPs (blue), SMSO@APTES NPs (green) and Composite (red).

The FTIR spectra of the SMSO and the resulting composite are presented in the Figure S2. Intense bands ranging from  $550\text{ cm}^{-1}$  to  $983\text{ cm}^{-1}$  are assigned to Si-O vibrations:  $983\text{ cm}^{-1}$  band assigned to the Si-O-Si asymmetric stretch;  $835$  and  $693\text{ cm}^{-1}$  bands assigned to Si-O symmetric stretching. They are all present in the three spectra of SMSO, SMSO@APTES and SMSO@APTES/HPMC[16].

The presence of APTES forming a silica-like shell is evident by the presence of the vibrational modes related to NH<sub>2</sub> and CH<sub>2</sub> in the SMSO@APTES SMSO@APTES/HPMC spectra. The band at  $3400\text{ cm}^{-1}$  is attributed to the asymmetric stretching of NH<sub>2</sub> in amines. The bands at  $2917\text{ cm}^{-1}$  and  $2837\text{ cm}^{-1}$  are assigned to stretching modes of CH<sub>2</sub> at alkanes and the  $1562\text{ cm}^{-1}$  assigned to the N-H bending of the amine groups[15].

A more detailed analysis of the Sr<sub>2</sub>MgSi<sub>2</sub>O<sub>7</sub> was made by Salim *et al.* and, based on their work, the majority of the bands of our material is presented in table S1.[14]

Table S1. Attribution of the main vibrational bands of SMSO, SMSO@APTES and SMSO@APTES/HPMC.

Attribution	Energy $cm^{-1}$
Si-O symmetric stretching	693
Si-O symmetric stretching	835
Si-O-Si asymmetric stretching	983
Sr-O-Si bending	1460
N-H bending	1549
Mg-O-Si stretching	1640
C-H stretching alkane	2837
C-H stretching alkane	2917
N-H stretching	3417

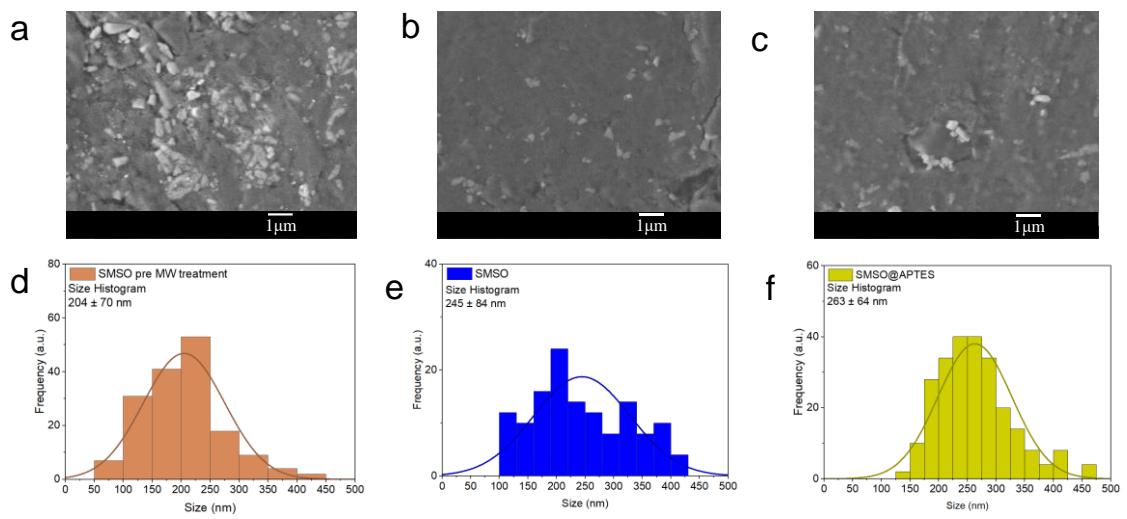


Figure S3: SEM images of (a) SMSO pre microwave (MW) treatment (precursor), (b) SMSO after MW treatment, and (c) of SMSO@APTES; Size histogram for of (d) SMSO pre MW treatment (precursor), (e) SMSO after MW treatment, and (f) of SMSO@APTES.

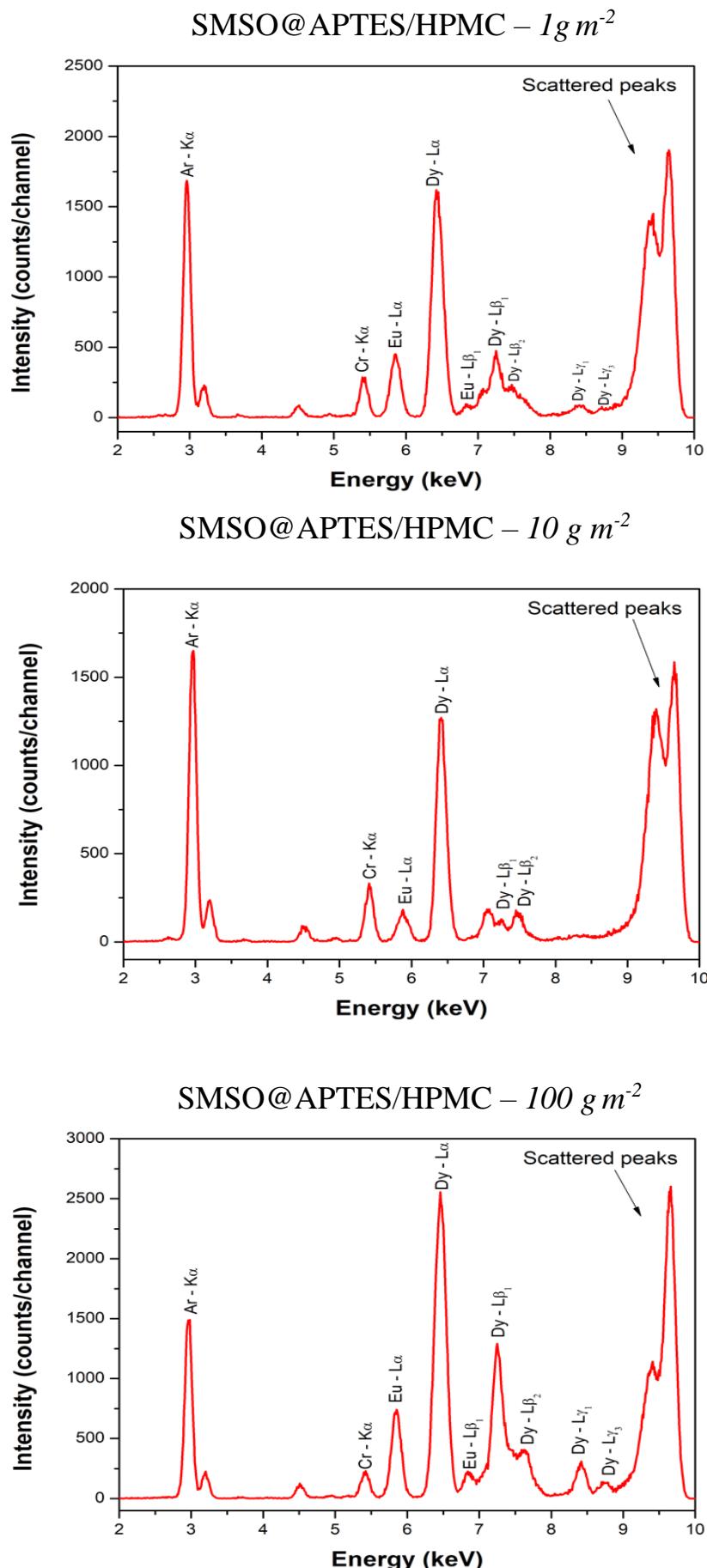


Figure S4: XRF spectra for SMSO@APTES/HPMC (a)  $1 g m^{-2}$ ; (b)  $10 g m^{-2}$  and (c)  $100 g m^{-2}$

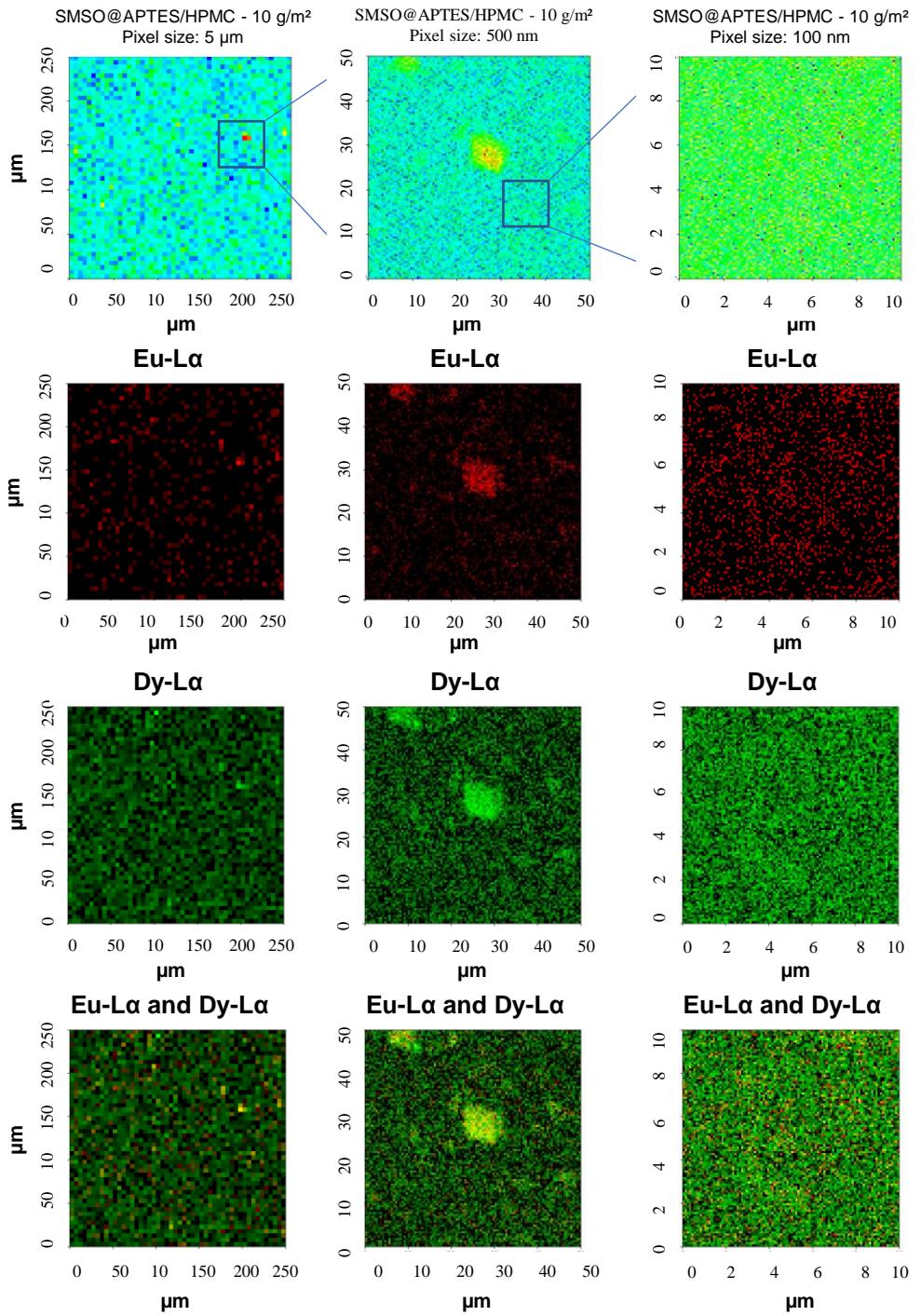


Figure S5: STXM images of SMSO@APTES/HPMC  $10 \text{ g}\cdot\text{m}^{-2}$  film at 9.656 keV. (b-d) XRF mapping of SMSO@APTES/HPMC  $10 \text{ g}\cdot\text{m}^{-2}$  film at (b) Eu L $\alpha$  (5.845 keV); (c) Dy L $\alpha$  (6.495 keV); (d) Eu and Dy L $\alpha$  lines under 9.656 keV excitation.

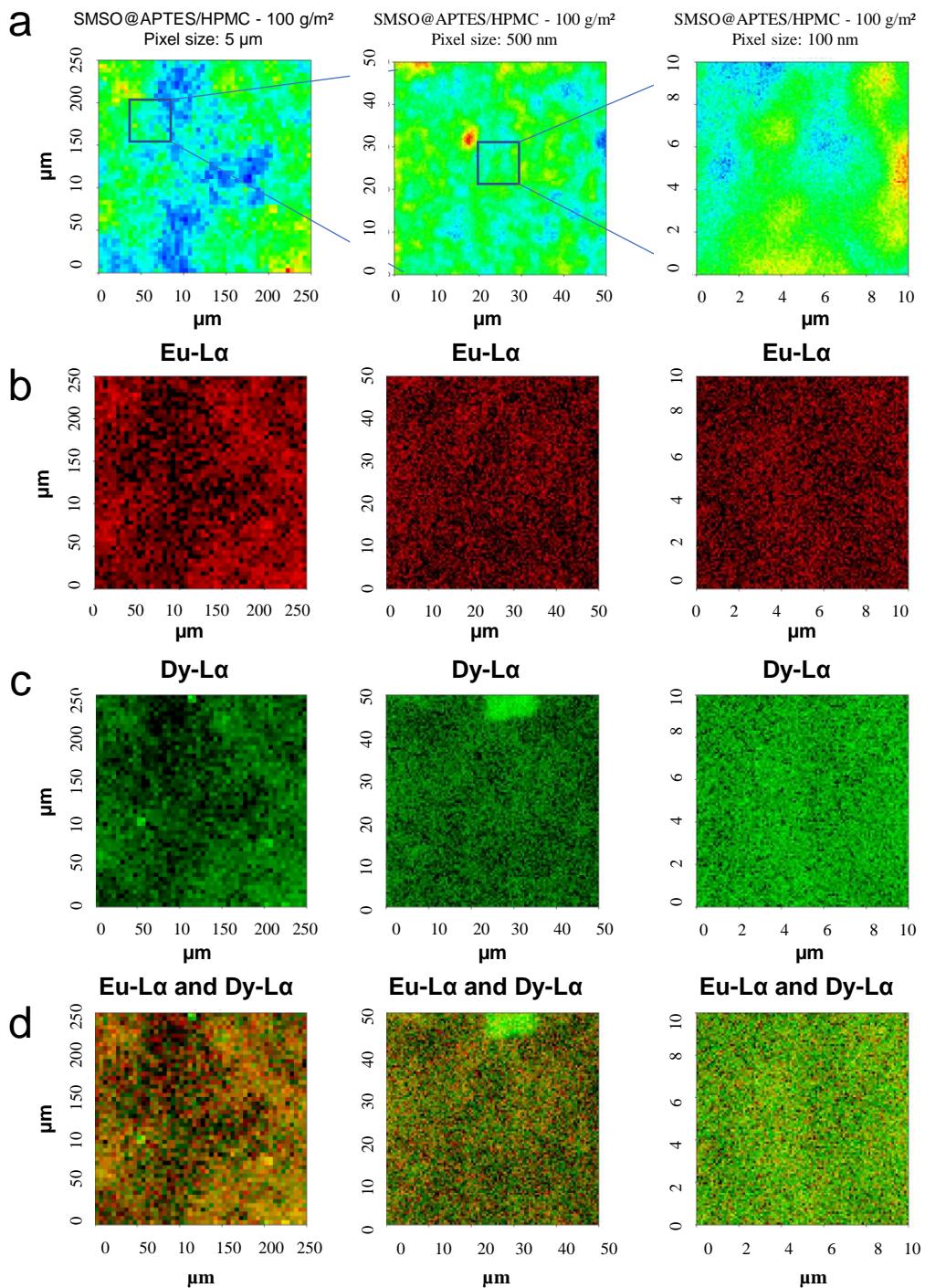


Figure S6: STXM images of SMSO@APTES/HPMC 100 g·m<sup>-2</sup> film at 9.656 keV. (b-d) XRF mapping of SMSO@APTES/HPMC 100 g m<sup>-2</sup> film at (b) Eu L $\alpha$  (5.845 keV); (c) Dy L $\alpha$  (6.495 keV); (d) Eu and Dy L $\alpha$  lines under 9.656 keV excitation.

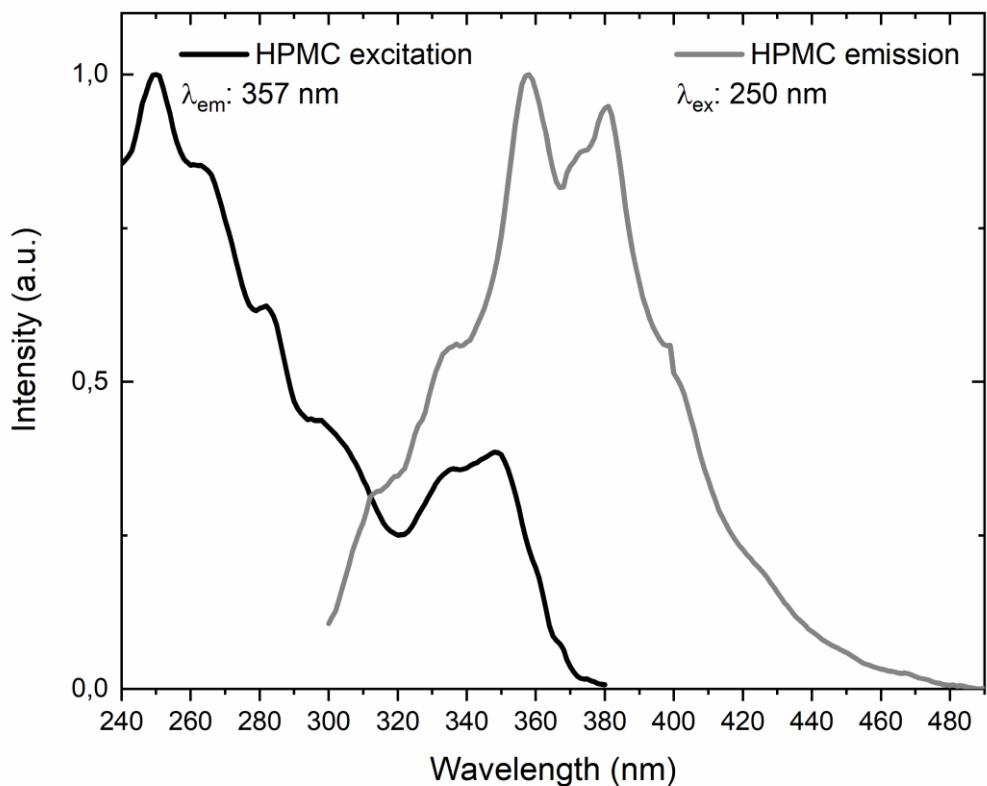


Figure S6: Excitation spectrum of HPMC measurement performed at room temperature, fixed excitation scan at  $357 \text{ nm}$  (black line) emission spectra of HPMC measurement performed at room temperature, fixed emission scan at  $250 \text{ nm}$  (gray line).

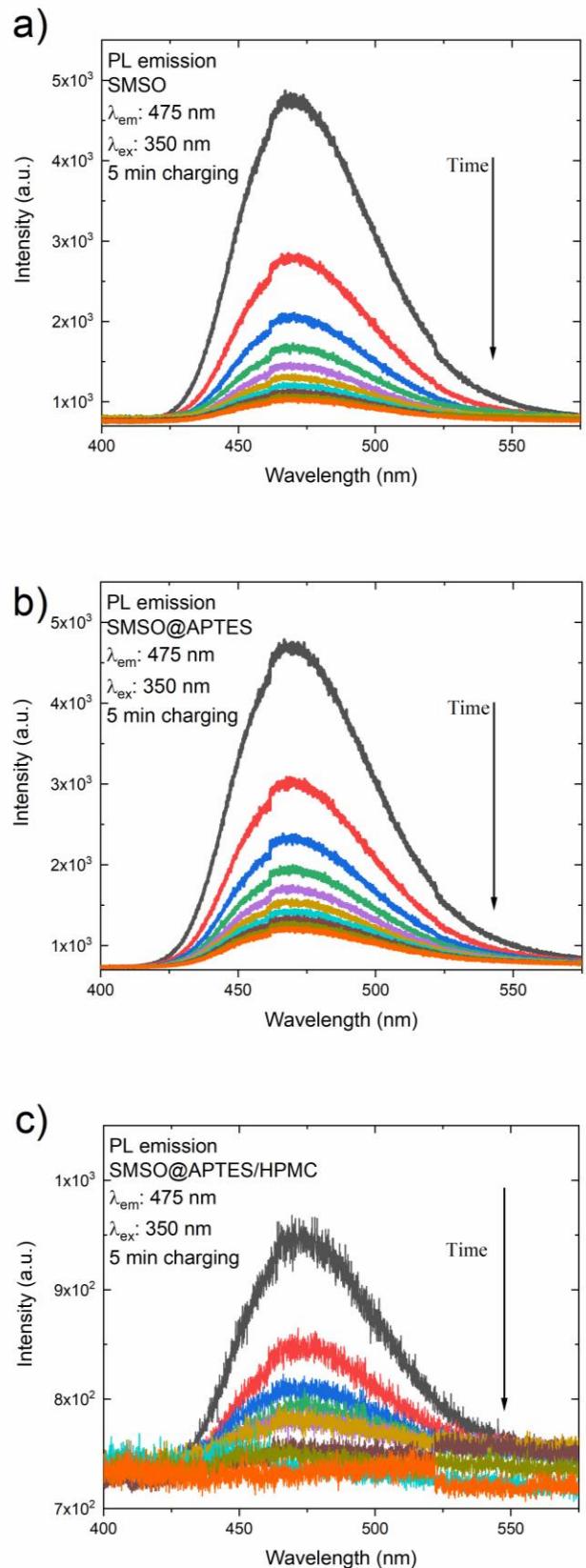


Figure S8: PL Emission Spectra of (a) SMSO, (b) SMSO@APTES, and (c) SMSO@APTES/HPMC with concentration of  $10 \text{ g m}^{-2}$ , monitored at 475 nm, after 5 min charging at 350 nm. Measurements with delay time of 1 min between measurements.

## Supplementary Material References

- [1] I. P. Sahu, D. P. Bisen, N. Brahme and R. K. Tamrakar, *J. Radiat. Res. Appl. Sci.*, 2015, **8**, 104–109.
- [2] S. Villa, P. Riani, F. Locardi and F. Canepa, *Mater. 2016, Vol. 9, Page 826*, 2016, **9**, 826.
- [3] M. A. Salim, R. Hussin, M. S. Abdullah, S. Abdullah, N. Shahira Alias, S. Aishah, A. Fuzi, M. Nor, M. Yusuf and K. M. Mahbor, *Solid State Sci. Technol.*, 2009, **17**, 59–64.